

Synchrotron XRPD

Fabia Gozzo



Excelsus Structural Solutions sprl, Brussels, Belgium

Excelsus Structural Solutions (Swiss) AG, Switzerland







fabia.gozzo@excels.us

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Outlook

- I. LoD and LoQ
- II. SR-XRPD: is a synchrotron source enough for trace analyses?
- III.Dose-controlled SR-XRPD
- IV. Qualitative and quantitative trace analyses of pharmaceuticals: requirements/difficulties



Quantitative Phase Analysis (QPA)

QPA refers to the ability of quantitatively state the abundance of the different phases that constitute a mixture.

Why is this relevant?

Polymorphic purity: detect and quantify unwanted polymorphic forms in both drug substance and drug product

- Level of Detection (LoD)
- Level of Quantitation (LoQ)

□ Assess the polymorphic composition in drug substance and product

In formulated materials, the API/excipients relative proportion is paramount and needs to be kept under control

Degree of Crystallinity in amorphous/crystalline mixtures



QPA of a binary API physical mixtures with fast SR-XRPD





Aggressive LoD/LoQ require advanced instrumentation often combined with advanced/unconventional methodologies



□ An intense photon beam for enhanced counting statistics

□ Adequate angular (FWHM) resolution

□ Adequate S/B and S/N



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Synchrotron XRPD

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www.excels.us



Our 3 ingredients for state-of-the-art SR-XRPD

- A. An efficient synchrotron facility and beamline optics
- B. State-of-the-art diffractometers
- C. Outstanding detection systems





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Hodeau et al, 1998

Schmitt et al, 2003, Bergamaschi, Schmitt et al, 2010



MYTHEN II



A. Synchrotron facility and beamline optics



Properties:

- High Spectral Brightness: 10¹²-10¹⁵ photons/sec in small beams (μm² to mm²)
- Tuneable and monochromatic photon energy
- Polarization
- Time structure
- Coherence

Benefits

- Efficient data collection, high statistics
- Time-resolved in-situ non ambient XRD
- Photon-consuming experimental set ups
- Penetration of highly absorbing materials
- Variable d-spacing resolution
- large unit cells (many reflections at very low angles)
- XRD near absorption edges (anomalous dispersion)



B. State-of-the-art diffractometers



Swiss Light Source-Materials Science beamline Powder Diffraction station



Properties:

Resolution: 1 arcsec

Accuracy: ±2 arcsec

Precision: ±1 arcsec

Large working space and flexibility

Benefits

- Great mechanical stability
- Highest flexibility to accommodate all kinds of sample environments



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C. Outstanding detection systems



Properties:

- > Angular selection of diffracted beam
- Fluorescence suppression

Benefits:

- Ultra-high resolution (better than 0.003°)
- Angular resolution independent of sample dimension and position
- > Independence of transparency effect
- High S/N and S/B

Trade-off:

Long measurements (min to hours) → radiation damage P Mythen II

Properties:

- Solid state modular microstrip detector
- Large dynamic range (24 bits)
- Single photon counting read out
- Fluorescence suppression
- Very fast acquisition times (subsec)

Schmitt et al, 2003, Bergamaschi, Schmitt et al, 2010

Benefits:

- ▶ 120° angular coverage at SLS
- High d-spacing resolution
- > 0.004° inherent angular resolution
- Capable of simultaneously detecting strong and weak signals
- Sub-sec time resolution XRPD for in-situ kinetic studies

Trade-off:

- > Resolution limited by sample dimension
- Sensitive to the uniformity of both the beam intensity spatial distribution and the powder distribution in sample holder, granularity, statistical orientation

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Minimization of radiation damage control with fast and dose-controlled SR-XRPD

- Radiation Damage is the alteration of the structural and chemical properties of the material under investigation induced by its exposure to electromagnetic radiation. It is dose and energy dependent
- ➤ In XRD patterns we observe shift (usually anisotropic) and broadening of reflections and their progressive disappearance → it usually undermines the success of structural solution

The effect is very serious at 3rd generation synchrotron facilities and affects the study of organic compounds, in particular pharmaceuticals

Our high-resolution, fast and dose controlled SR-XRPD measurements have opened a new gate to the systematic structural analyses of organic compounds!







With pharmaceuticals, radiation damage control is particularly critical when aiming at very low LoD and LoQ



What are the requirements/difficulties related to qualitative and quantitative trace analyses in pharmaceuticals?



Trace analysis \rightarrow signal from minority phase extremely weak

- □ Require unusual counting statistics (orders of hundreds of million of counts) \rightarrow Is this enough?
- □ Reduced non-statistical noise → single photon counting detectors, reduced background, accurate flat field calibrations, tunable photon energy



Trace analysis \rightarrow dilution of the minority phase

- □ Particle Statistics, often combined with Preferential Orientation
- □ Peak line shape with position sensitive detectors



API mixture: 99.95% Haloperidol + 0.05% Indomethacin







Trace analysis \rightarrow dilution of the minority phase

- □ Particle Statistics, often combined with Preferential Orientation
- □ Peak line shape with position sensitive detectors
- □ `anisotropic' shifts of minority phase peaks

- ➤ Much larger volumes of powder should be analyzed → in transmission geometry with capillaries, larger diameter → reduced angular (FWHM) resolution
- > Sample spun for improved orientation statistics
- Powder mechanical comminution (not always possible!)



Tuning the synchrotron optics to improve LoD and LoQ

(R&D work in progress)



Our pilot experiments have demonstrated LoD down to 0.01% in *ad-hoc* API mixtures

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Unconventional beam optics

QPA by XRPD 14th PPXRD Workshop June 5th, 2016 – Fort Myers-FL



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The accuracy of the quantitative phase analysis strongly depends on:

- The quality of the refinement models
- How close to the correct values of all these refinement parameters we start the quantitative analysis

When dealing with quantification of traces:

- All contributions in the diffraction pattern should be appropriately described to drastically reduce the number of refined parameters and the correlations of refined parameters during QPA
- The minority phase parameters do not support refinement during QPA analysis and should not be refined



A good description of the extrinsic background with a limited number of parameters





Thanks for your kind attention